

**Notice of References Cited**

Application/Control No.

10/559,739

Applicant(s)/Patent Under  
Reexamination  
DEMLER ET AL.

Examiner

Bena Miller

Art Unit

3725

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0070303 A1	06-2002	Johansson et al.	241/261.3
*	B	US-2003/0071153 A1	04-2003	Aikawa, Yoshihiko	241/246
*	C	US-6,617,720 B1	09-2003	Egan et al.	310/67R
*	D	US-2005/0247808 A1	11-2005	Huhtanen et al.	241/261.1
*	E	US-7,508,194 B2	03-2009	.ANG.kerblom, Bengt	324/207.13
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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